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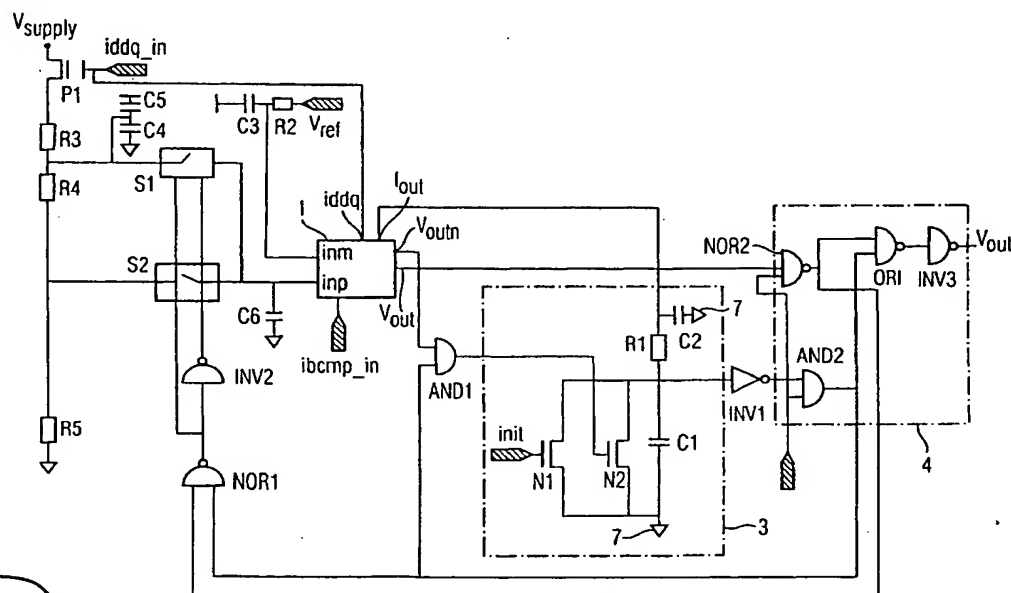
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(54) Title: UNDER-VOLTAGE DETECTION CIRCUIT



(57) Abstract: An under-voltage detection (UVD) circuit includes a comparator 1 for determining the amount by which a voltage supply V_{supply} falls short of a reference voltage V_{ref} , and an integrator 3 for time-integrating this shortfall. In a glitch immune operating mode of the UVD circuit, a reset is generated using this integrated value. A reset is only generated in the case that a glitch in the supply voltage V_{supply} has a duration longer than a critical duration. The critical duration depends upon the magnitude of the glitch and the component values of the integrator 3.

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